Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LEE ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,661,181	12-2003	Shin, Chung-Hyuk	315/169.4
*	В	US-6,812,921	11-2004	Hsu, Alpha	345/211
*	С	US-2001/0011980	08-2001	Jang, Kyeong-Kun	345/87
*	D	US-2002/0154080	10-2002	Miyazaki, Kiyoshi	345/87
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s	<u> </u>				
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.